STGP10NC60H

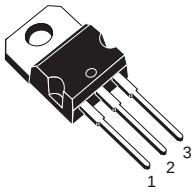
N-CHANNEL 10A - 600V - TO-220
VERY FAST PowerMESH™ IGBT

TARGET SPECIFICATION

General features

Type	V_{CES}	$V_{CE(sat)}$ (Max)@ 25°C	I_C @100°C
STGP10NC60H	600V	< 2.5V	10A

- LOWER ON-VOLTAGE DROP (V_{cesat})
- LOWER C_{RES} / C_{IES} RATIO (NO CROSS-CONDUCTION SUSCEPTIBILITY)
- VERY SOFT ULTRA FAST RECOVERY ANTIPARALLEL DIODE

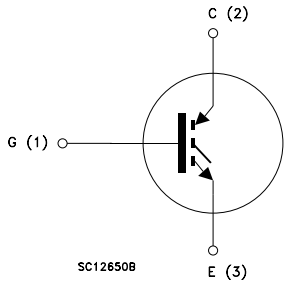


TO-220

Description

Using the latest high voltage technology based on a patented strip layout, STMicroelectronics has designed an advanced family of IGBTs, the PowerMESH™ IGBTs, with outstanding performances. The suffix "H" identifies a family optimized for high frequency applications in order to achieve very high switching performances (reduced tfall) mantaining a low voltage drop.

Internal schematic diagram



Applications

- HIGH FREQUENCY MOTOR CONTROLS
- SMPS and PFC IN BOTH HARD SWITCH AND RESONANT TOPOLOGIES
- MOTOR DRIVERS

Order codes

Sales Type	Marking	Package	Packaging
STGP10NC60H	P10NC60H	TO-220	TUBE

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CES}	Collector-Emitter Voltage (V_{GS} = 0)	600	V
I_C *Note* 5	Collector Current (continuous) at T_C = 25°C	20	A
I_C *Note* 5	Collector Current (continuous) at T_C = 100°C	10	A
I_{CM} *Note* 1	Collector Current (pulsed)	40	W
V_{GE}	Gate-Emitter Voltage	±20	A
P_{TOT}	Total Dissipation at T_C = 25°C	60	W
T_{stg}	Storage Temperature	– 55 to 150	°C
T_j	Operating Junction Temperature		
T_l	Maximum Lead Temperature For Soldering Purpose (for 10sec. 1.6 mm from case)	300	°C

Table 2. Thermal resistance

Rthj-case	Thermal Resistance Junction-case Max	2.08	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	62.5	°C/W

2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

Table 3. On/Off

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{BR(CES)}$	Collector-Emitter Breakdown Voltage	I_C= 1mA, V_{GE}= 0	600			V
I_{CES}	Collector cut-off Current (V_{GE} = 0)	V_{CE}= Max Rating,T_C= 25°C V_{CE}=Max Rating,T_C= 125°C			10 1	µA mA
I_{GES}	Gate-Emitter Leakage Current (V_{CE} = 0)	V_{GE}= ±20V , V_{CE}= 0			±100	nA
$V_{GE(th)}$	Gate Threshold Voltage	V_{CE}= V_{GE}, I_C= 250µA	5		7	V
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	V_{GE}= 15V, I_C= 5A V_{GE}= 15V, I_C= 5A, Tc= 125°C		1.9 1.7	2.5	V V
g_{fs}	Forward Transconductance	V_{CE} = 15V, I_C= 5A		TBD		S

Table 4. Dynamic

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
C_{ies} C_{oes} C_{res}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V_{CE} = 25V, f = 1MHz,V_{GE} = 0		TBD TBD TBD		pF pF pF
Q_g Q_{ge} Q_{gc}	Total Gate Charge Gate-Emitter Charge Gate-Collector Charge	V_{CE} = 390V, I_C = 5A, V_{GE} = 15V, (see Figure 2)		TBD TBD TBD		nC nC nC

Table 5. Switching On/Off (inductive load)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r $(di/dt)_{on}$	Turn-on Delay Time Current Rise Time Turn-on Current Slope	V_{CC} = 390V, I_C = 5A R_G= 10Ω, V_{GE}= 15V, Tj= 25°C (see Figure 3)		TBD TBD TBD		ns ns A/µs
$t_{d(on)}$ t_r $(di/dt)_{on}$	Turn-on Delay Time Current Rise Time Turn-on Current Slope	V_{CC} = 390V, I_C = 5A R_G= 10Ω, V_{GE}= 15V, Tj=125°C (see Figure 3)		TBD TBD TBD		ns ns A/µs
$t_r(V_{off})$ $t_{d(off)}$ t_f	Off Voltage Rise Time Turn-off Delay Time Current Fall Time	V_{cc} = 390V, I_C = 5A, R_{GE} = 10Ω , V_{GE} = 15V,T_J=25°C (see Figure 3)		TBD TBD TBD		ns ns ns
$t_r(V_{off})$ $t_{d(off)}$ t_f	Off Voltage Rise Time Turn-off Delay Time Current Fall Time	V_{cc} = 390V, I_C = 5A, R_{GE}=10Ω , V_{GE} =15V, Tj=125°C (see Figure 3)		TBD TBD TBD		ns ns ns

Table 6. Switching energy (inductive load)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Eon *Note* 3 E_{off} *Note* 4 E_{ts}	Turn-on Switching Losses Turn-off Switching Losses Total Switching Losses	V_{CC} = 390V, I_C = 75A R_G= 10Ω, V_{GE}= 15V, Tj= 25°C (see Figure 3)		TBD TBD TBD		µJ µJ µJ
Eon *Note* 3 E_{off} *Note* 4 E_{ts}	Turn-on Switching Losses Turn-off Switching Losses Total Switching Losses	V_{CC} = 390V, I_C = 5A R_G= 10Ω, V_{GE}= 15V, Tj= 125°C (see Figure 3)		TBD TBD TBD		µJ µJ µJ

(1)Pulse width limited by max. junction temperature

(2) Pulsed: Pulse duration = 300 µs, duty cycle 1.5%

(3) Eon is the tun-on losses when a typical diode is used in the test circuit in figure 2 Eon include diode recovery energy. If the IGBT is offered in a package with a co-pak diode, the co-pack diode is used as external diode. IGBTs & Diode are at the same temperature (25°C and 125°C)

(4) Turn-off losses include also the tail of the collector current

(5) Calculated according to the iterative formula:

$$I_C(T_C) = \frac{T_{JMAX} - T_C}{R_{THJ-C} \times V_{CESAT(MAX)}(T_C, I_C)}$$

3 Test Circuits

Figure 1. Test Circuit for Inductive Load Switching

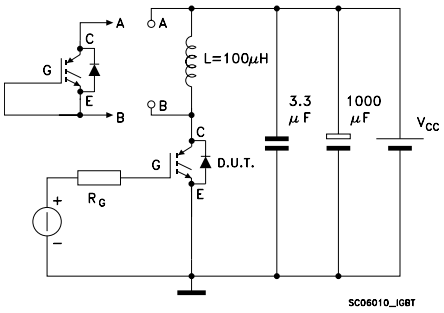


Figure 2. Gate Charge Test Circuit

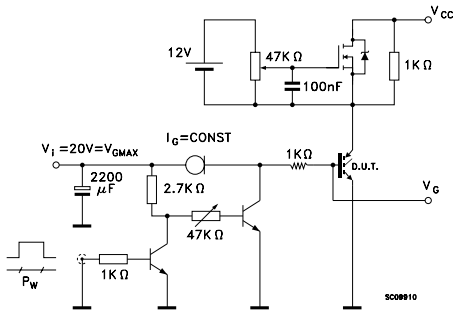
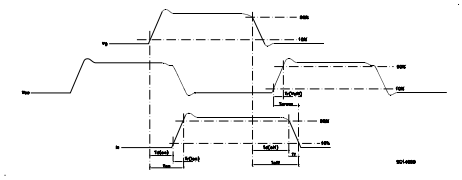


Figure 3. Switching Waveform

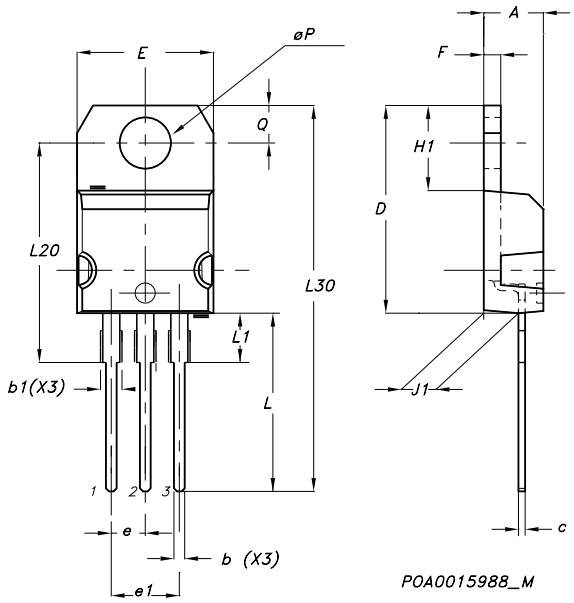


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

TO-220 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.15		1.70	0.045		0.066
c	0.49		0.70	0.019		0.027
D	15.25		15.75	0.60		0.620
E	10		10.40	0.393		0.409
e	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.052
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
øP	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116



5 Revision History

Date	Revision	Changes
18-Nov-2005	1	Initial release.